N-Channel Power MOSFET 500 V, 0.52 Ω

Features

- Low ON Resistance
- Low Gate Charge
- 100% Avalanche Tested
- These Devices are Pb-Free and are RoHS Compliant

ABSOLUTE MAXIMUM RATINGS (T_C = 25°C unless otherwise noted)

Rating	Symbol	NDF11N50Z	NDP11N50Z	Unit
Drain-to-Source Voltage	V_{DSS}	500		V
Continuous Drain Current, $R_{\theta JC}$	I _D	10.5 (Note 10.5 2)		Α
Continuous Drain Current $T_A = 100^{\circ}C, R_{\theta JC}$	I _D	6.7 (Note 2)	6.7	Α
Pulsed Drain Current, V _{GS} @ 10 V	I _{DM}	42 (Note 2)	42	Α
Power Dissipation, $R_{\theta JC}$ (Note 1)	P _D	36	145	W
Gate-to-Source Voltage	V _{GS}	±30		V
Single Pulse Avalanche Energy, I _D = 10.5 A	E _{AS}	190		mJ
ESD (HBM) (JESD22-A114)	V _{esd}	4000		V
RMS Isolation Voltage (t = 0.3 sec., R.H. \leq 30%, T _A = 25°C) (Figure 14)	V _{ISO}	4500		V
Peak Diode Recovery	dv/dt	4.5 (Note 3)		V/ns
Continuous Source Cur- rent (Body Diode)	I _S	10.5		Α
Maximum Temperature for Soldering Leads	TL	260		°C
Operating Junction and Storage Temperature Range	T _J , T _{stg}	-55 to 150		°C

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

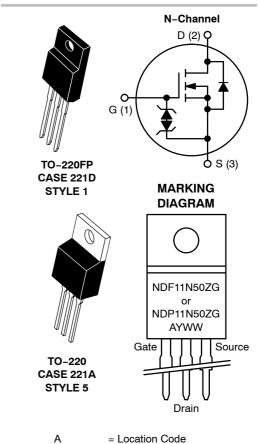
- Surface mounted on FR4 board using 1" sq. pad size, (Cu area = 1.127 in sq [2 oz] including traces).
- 2. Limited by maximum junction temperature
- 3. $I_d \le 10.5 \, \text{Å}, \, di/dt \le 200 \, \text{A}/\mu \text{s}, \, V_{DD} \le BV_{DSS}, \, T_J \le 150^{\circ} \text{C}.$



ON Semiconductor®

http://onsemi.com

V _{DSS}	R _{DS(ON)} (MAX) @ 4.5 A
500 V	0.52 Ω



Y = Year

Y = Year WW = Work Week

G = Pb-Free Package

ORDERING INFORMATION

See detailed ordering and shipping information in the package dimensions section on page 6 of this data sheet.

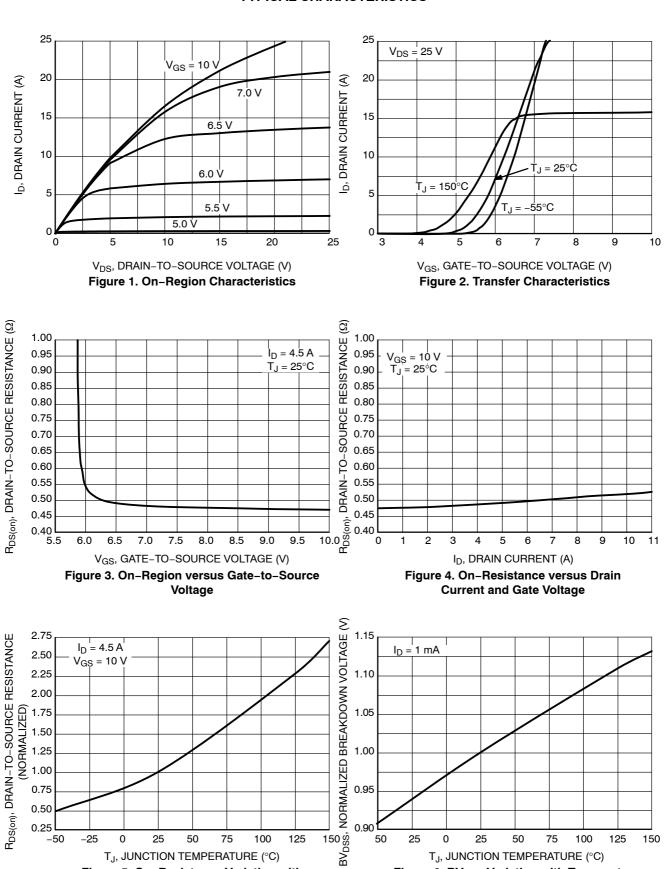
THERMAL RESISTANCE

Parameter	Symbol	NDF11N50Z	NDP11N50Z	Unit
Junction-to-Case (Drain)	$R_{\theta JC}$	3.4	0.9	°C/W
Junction-to-Ambient Steady State (Note 4)	$R_{\theta JA}$	50	50	

Characteristic	Test Conditions		Symbol	Min	Тур	Max	Unit
OFF CHARACTERISTICS							•
Drain-to-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}$	\	BV _{DSS}	500			V
Breakdown Voltage Temperature Coefficient	Reference to 25°C, I _D = 1 mA		$\Delta BV_{DSS}/$ ΔT_{J}		0.6		V/°C
Drain-to-Source Leakage Current		25°C	I _{DSS}			1	μΑ
	$V_{DS} = 500 \text{ V}, V_{GS} = 0 \text{ V}$	125°C				50	
Gate-to-Source Forward Leakage	V _{GS} = ±20 V		I _{GSS}			±10	μА
ON CHARACTERISTICS (Note 5)							
Static Drain-to-Source On-Resistance	$V_{GS} = 10 \text{ V}, I_D = 4.5 \text{ A}$	4	R _{DS(on)}		0.48	0.52	Ω
Gate Threshold Voltage	V _{DS} = V _{GS} , I _D = 100 μ	A	V _{GS(th)}	3.0		4.5	V
Forward Transconductance	V _{DS} = 15 V, I _D = 4.5 A		9FS		7.7		S
DYNAMIC CHARACTERISTICS							
Input Capacitance			C _{iss}		1375		pF
Output Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz		C _{oss}		166		
Reverse Transfer Capacitance			C _{rss}		40		
Total Gate Charge			Qg		46		nC
Gate-to-Source Charge	V _{DD} = 250 V, I _D = 10.5	Α,	Q _{gs}		8.7		
Gate-to-Drain ("Miller") Charge	$V_{GS} = 10 \text{ V}$		Q _{gd}		25		
Plateau Voltage			V_{GP}		6.2		V
Gate Resistance			R_g		1.4		Ω
RESISTIVE SWITCHING CHARACTER	STICS						
Turn-On Delay Time			t _{d(on)}		15		ns
Rise Time	V _{DD} = 250 V, I _D = 10.5	Α,	t _r		32		1
Turn-Off Delay Time	$V_{GS} = 10 \text{ V}, R_G = 5 \Omega$		t _{d(off)}		40		1
Fall Time			t _f		23		1
SOURCE-DRAIN DIODE CHARACTER	ISTICS (T _C = 25°C unless oth	erwise not	ed)				-
Diode Forward Voltage	I _S = 10.5 A, V _{GS} = 0		V _{SD}			1.6	V
Reverse Recovery Time	V _{GS} = 0 V, V _{DD} = 30	V	t _{rr}		310		ns
Reverse Recovery Charge	I _S = 10.5 A, di/dt = 100 A/μs		Q _{rr}		2.5		μС

^{4.} Insertion mounted
5. Pulse Width ≤ 380 μs, Duty Cycle ≤ 2%.

TYPICAL CHARACTERISTICS



T_J, JUNCTION TEMPERATURE (°C)

Figure 6. BV_{DSS} Variation with Temperature

T_J, JUNCTION TEMPERATURE (°C)

Figure 5. On-Resistance Variation with

Temperature

TYPICAL CHARACTERISTICS

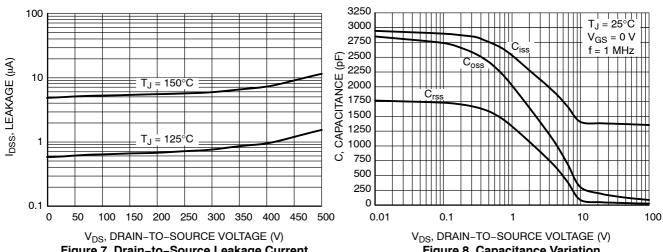


Figure 7. Drain-to-Source Leakage Current versus Voltage

Figure 8. Capacitance Variation

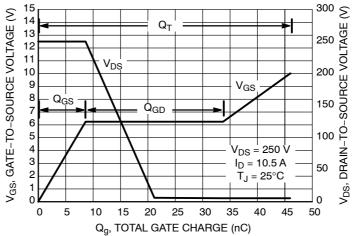


Figure 9. Gate-to-Source Voltage and Drain-to-Source Voltage versus Total Charge

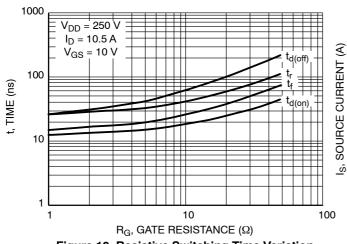


Figure 10. Resistive Switching Time Variation versus Gate Resistance

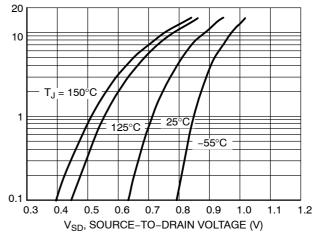


Figure 11. Diode Forward Voltage versus Current

TYPICAL CHARACTERISTICS

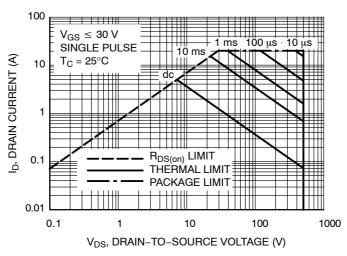


Figure 12. Maximum Rated Forward Biased Safe Operating Area NDF11N50Z

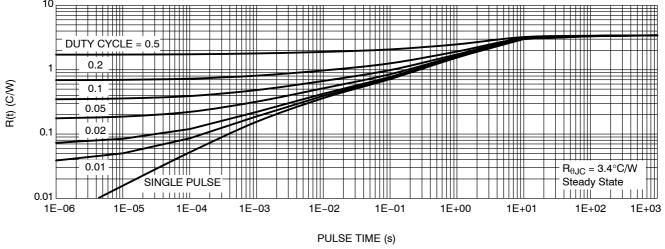


Figure 13. Thermal Impedance (Junction-to-Case) for NDF11N50Z

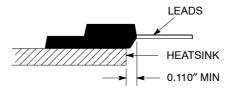


Figure 14. Isolation Test Diagram

Measurement made between leads and heatsink with all leads shorted together.

*For additional mounting information, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

DataSheet

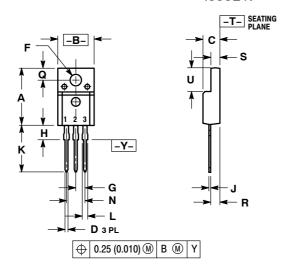
NDF11N50Z, NDP11N50Z

ORDERING INFORMATION

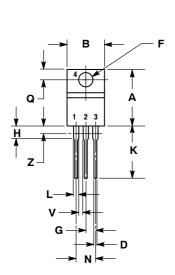
Order Number	Package	Shipping	
NDF11N50ZG	TO-220FP (Pb-Free)	50 Units / Rail	
NDP11N50ZG	TO-220AB (Pb-Free)	50 Units / Rail (In Development)	

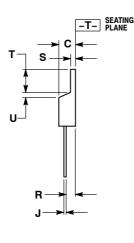
PACKAGE DIMENSIONS

TO-220FP CASE 221D-03 **ISSUE K**



TO-220 CASE 221A-09 **ISSUE AF**





- 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
 2. CONTROLLING DIMENSION: INCH
- 221D-01 THRU 221D-02 OBSOLETE, NEW STANDARD 221D-03

	INC	INCHES		IETERS		
DIM	MIN	MAX	MIN	MAX		
Α	0.617	0.635	15.67	16.12		
В	0.392	0.419	9.96	10.63		
c	0.177	0.193	4.50	4.90		
D	0.024	0.039	0.60	1.00		
F	0.116	0.129	2.95	3.28		
G	0.100	0.100 BSC		2.54 BSC		
Н	0.118	0.135	3.00	3.43		
J	0.018	0.025	0.45	0.63		
K	0.503	0.541	12.78	13.73		
L	0.048	0.058	1.23	1.47		
N	0.200	BSC	5.08 BSC			
Q	0.122	0.138	3.10	3.50		
R	0.099	0.117	2.51	2.96		
S	0.092	0.113	2.34	2.87		
U	0.239	0.271	6.06	6.88		

PIN 1. GATE

2. DRAIN SOURCE

NOTES:

- DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982
- CONTROLLING DIMENSION: INCH.
 DIMENSION Z DEFINES A ZONE WHERE ALL **BODY AND LEAD IRREGULARITIES ARE** ALLOWED

	INCHES		MILLIMETERS		
DIM	MIN	MAX	MIN	MAX	
Α	0.570	0.620	14.48	15.75	
В	0.380	0.405	9.66	10.28	
С	0.160	0.190	4.07	4.82	
D	0.025	0.035	0.64	0.88	
F	0.142	0.161	3.61	4.09	
G	0.095	0.105	2.42	2.66	
Н	0.110	0.155	2.80	3.93	
J	0.014	0.025	0.36	0.64	
K	0.500	0.562	12.70	14.27	
L	0.045	0.060	1.15	1.52	
N	0.190	0.210	4.83	5.33	
Q	0.100	0.120	2.54	3.04	
R	0.080	0.110	2.04	2.79	
S	0.045	0.055	1.15	1.39	
Т	0.235	0.255	5.97	6.47	
U	0.000	0.050	0.00	1.27	
٧	0.045		1.15		
Z		0.080		2.04	

STYLE 5: PIN 1.

GATE 2.

DRAIN 3. SOURCE

DRAIN

ON Semiconductor and un are registered trademarks of Semiconductor Components Industries, LLC (SCILLC). SCILLC reserves the right to make changes without further notice on semiconductor and are registered readerlands of semiconductor Components industries, ILC (SCILLC). SciLLC reserves are right to finate changes without further holice to any products herein. SCILLC makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does SCILLC assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. "Typical" parameters which may be provided in SCILLC data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. SCILLC does not convey any license under its patent rights nor the rights of others. SCILLC products are not designed, intended, or authorized for use as components in systems intended for surgical implant into the body, or other applications intended to support or sustain life, or for any other application in which the failure of the SCILLC product could create a situation where personal injury or death may occur. Should Buyer purchase or use SCILLC products for any such unintended or unauthorized application, Buyer shall indemnify and hold SCILLC and its officers, employees, subsidiaries, affiliates, and distributors harmless against all claims, costs, damages, and expenses, and reasonable attorney fees arising out of, directly or indirectly, any claim of personal injury or death associated in the state of the SCILLC and its officers, employees, subsidiaries, affiliates, and distributors harmless against all claims, costs, damages, and expenses, and reasonable attorney fees arising out of, directly or indirectly, any claim of personal injury or death associated in the state of the SCILLC and its officers. ated with such unintended or unauthorized use, even if such claim alleges that SCILLC was negligent regarding the design or manufacture of the part. SCILLC is an Equal Opportunity/ Affirmative Action Employer. This literature is subject to all applicable copyright laws and is not for resale in any manner.

PUBLICATION ORDERING INFORMATION

LITERATURE FULFILLMENT:

Literature Distribution Center for ON Semiconductor P.O. Box 5163, Denver, Colorado 80217 USA

Phone: 303-675-2175 or 800-344-3860 Toll Free USA/Canada Fax: 303-675-2176 or 800-344-3867 Toll Free USA/Canada Email: orderlit@onsemi.com

N. American Technical Support: 800-282-9855 Toll Free USA/Canada

Europe, Middle East and Africa Technical Support: Phone: 421 33 790 2910

Japan Customer Focus Center Phone: 81-3-5773-3850

ON Semiconductor Website: www.onsemi.com

Order Literature: http://www.onsemi.com/orderlit

For additional information, please contact your local Sales Representative